

TECHSPEC[®] 25.4mm Dia., 1mm Thick, 355nm, Nd:YAG Laser Line Beam Sampler



TECHSPEC[®] Thin Nd:YAG Laser Line Beam Samplers

Stock **#29-019** 7 In Stock

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1

+

€169⁰⁰

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Volume Pricing	
Qty 1-5	€169,00 each
Qty 6-25	€152,00 each
Qty 26-49	€135,00 each
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ⓘ Prices shown are exclusive of VAT/local taxes

Product Downloads

SPECIFICATIONS

General

Beam Sampler

Type:

Physical & Mechanical Properties	
25.40 +0.00/-0.10	Diameter (mm):
1.00 ±0.10	Thickness (mm):
<0.50	Parallelism (arcmin):
90	Clear Aperture (%):
Optical Properties	
0 ±5	Angle of Incidence (°):
Laser V-Coat (355nm)	Coating:
355	Design Wavelength DWL (nm):
Fused Silica (Corning 7980)	Substrate: ☐
1.458	Index of Refraction (n _d):
20-10	Surface Quality:
R _{abs} <0.25% @ 355nm @ 0 ±5° AOI	Coating Specification:
7.5 J/cm ² @ 355nm, 20ns, 20Hz	Damage Threshold, By Design: ☐
0.167 @ 632.8nm	Transmitted Wavefront Distortion:
Regulatory Compliance	
View	Certificate of Conformance:

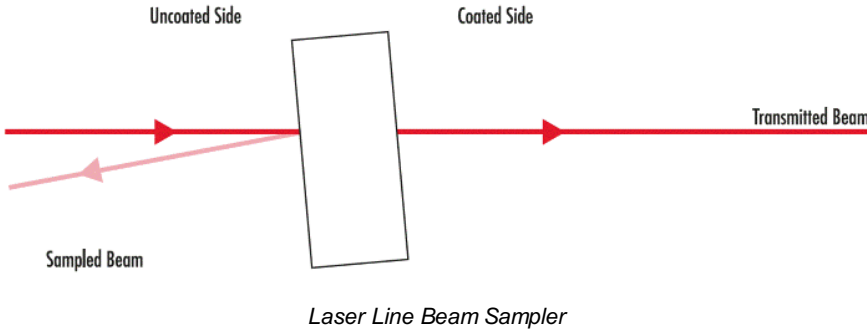
PRODUCT DETAILS

- Thin 1mm Design for Space and Weight Constrained Applications
- Uncoated First Surface Provides Fresnel Reflection
- AR Coated Second Surface Provides High Transmission
- High Laser Damage Threshold to Prevent Laser Ablation

TECHSPEC® Thin Nd:YAG Laser Line Beam Samplers are designed to isolate a small portion of incident beams via Fresnel reflection and anti-reflection properties for beam monitoring purposes. These beam samplers are designed with a 1mm thickness to facilitate applications where space and weight constraints are critical. Additionally, an anti-reflection (AR) coating with a high damage threshold on surface two maximizes transmission and reduces ghost reflections. These second surface coated beam samplers are available in laser line coatings including 266nm, 355nm, 532nm, and 1064nm wavelengths. TECHSPEC® Thin Nd:YAG Laser Line Beam Samplers feature a UV Fused Silica substrate which provides excellent transmission from the UV to the IR and a low coefficient of thermal expansion. These beam samplers are ideal for applications where monitoring beam power, wavefront distortion, and optical losses are required.

Note: TECHSPEC® Thin Nd:YAG Laser Line Beam Samplers can be used with [Laser Measurement](#) products to monitor beam properties, such as beam power and beam profile, in real time.

TECHNICAL INFORMATION



COMPATIBLE MOUNTS